

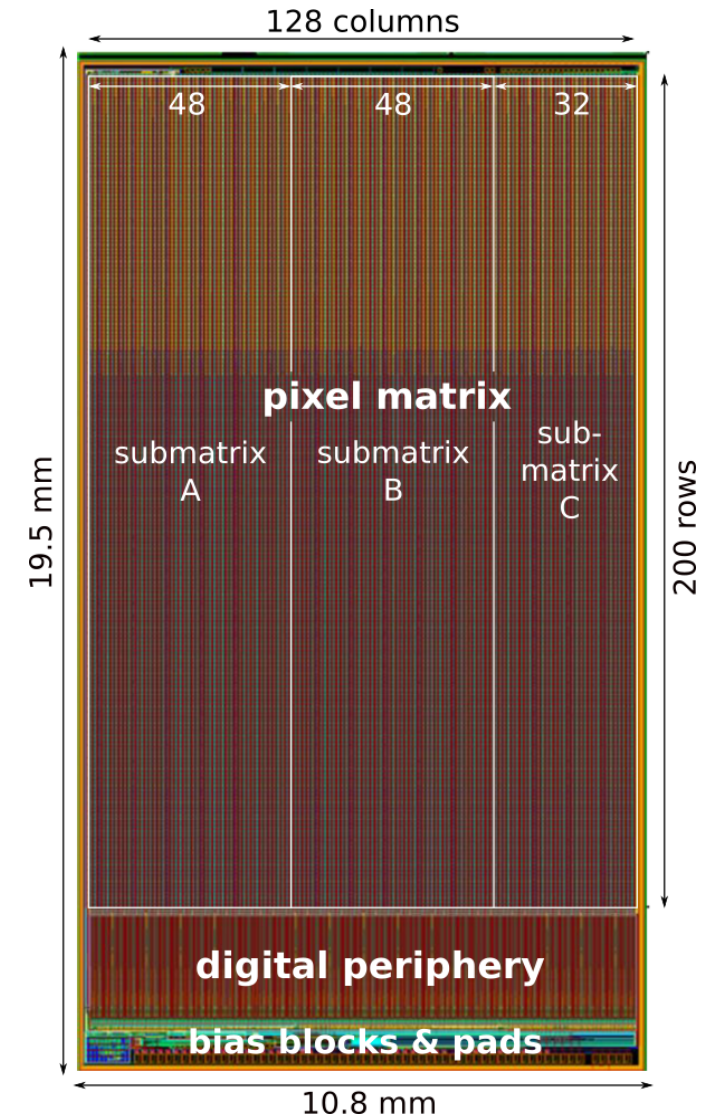
MuPix8: Status Update

**– PANDA Collaboration Meeting 2018/3 –
Luminosity Detector Session**

René Hagdorn
Darmstadt, November 6, 2018

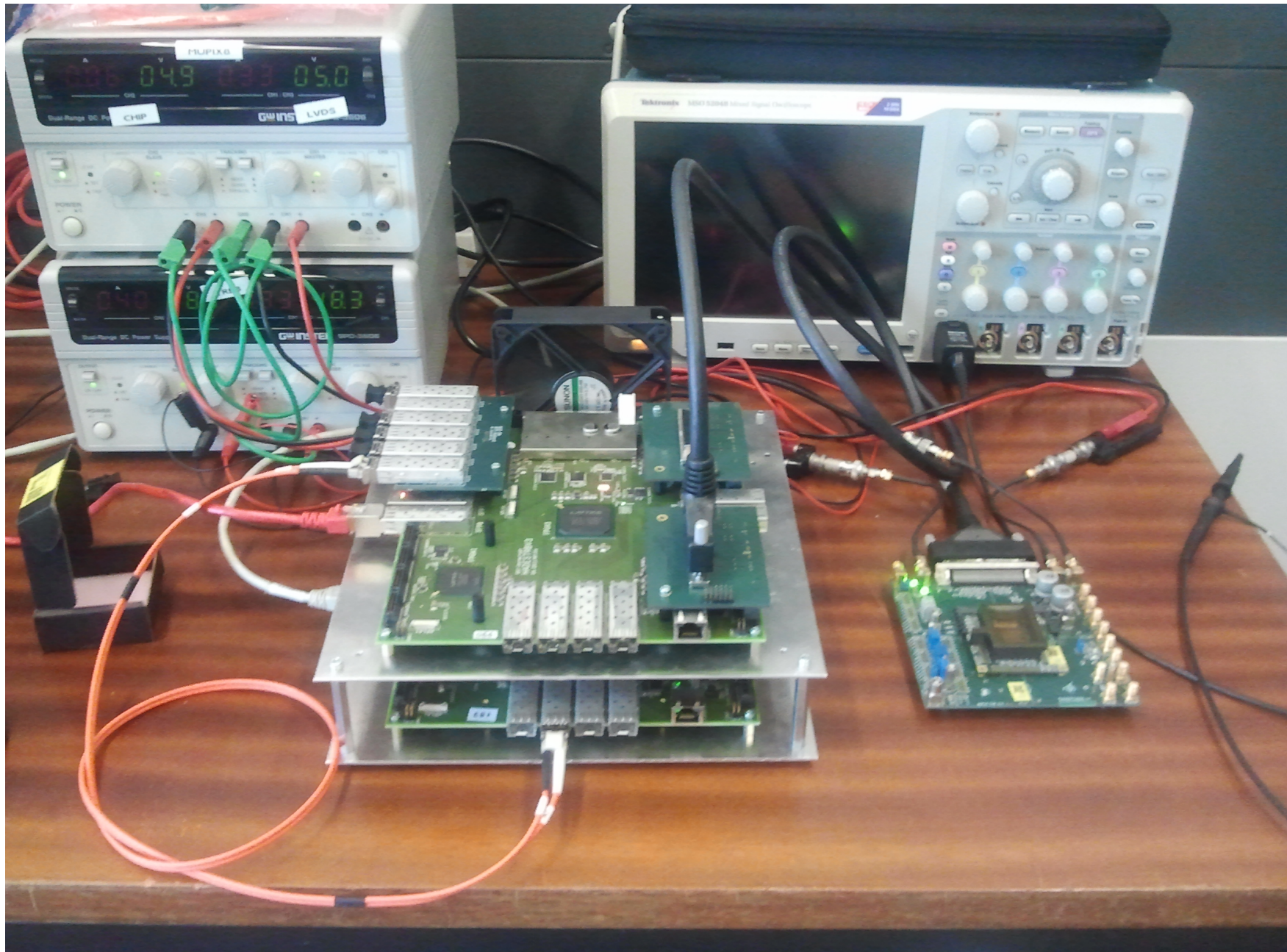
- Based on HV-MAPS concept
- Physical size: $10.8 \times 19.5 \text{ mm}^2$
- Active area: $\sim 10.2 \times 16.2 \text{ mm}^2$
- Matrix: 128×200 Pixels divided into 3 Submatrices
- Pixel: $80 \times 81 \mu\text{m}^2$, single diode

- Charge sensitive amplifier in each pixel
- Two comparators in periferal cells
- 4 LVDS links @ 1.25 Gbit/s
- Analog readout of Hitbus (ToT information)
- Amplifier output (for leftmost column only)

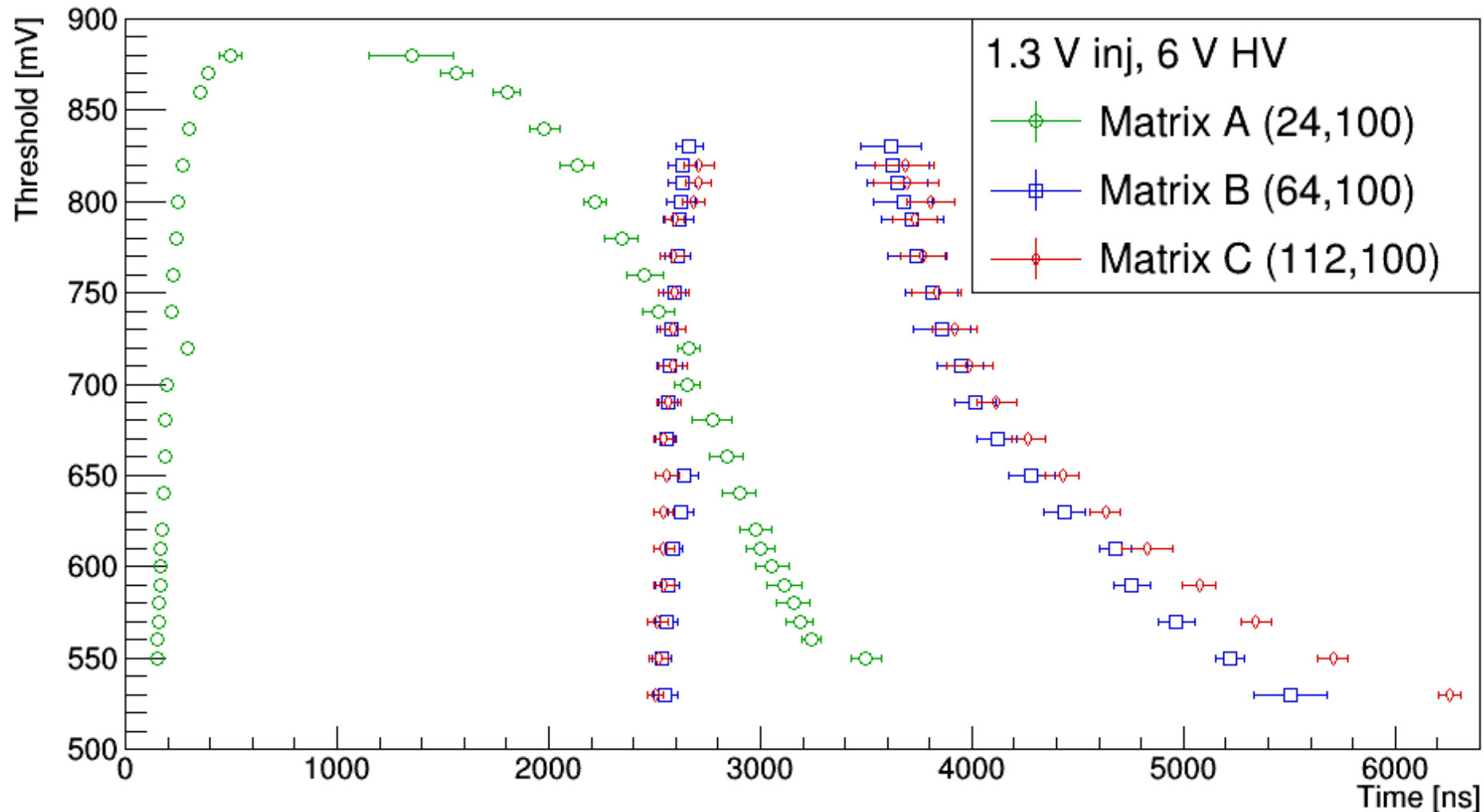


Lab Measurements – Analog Properties

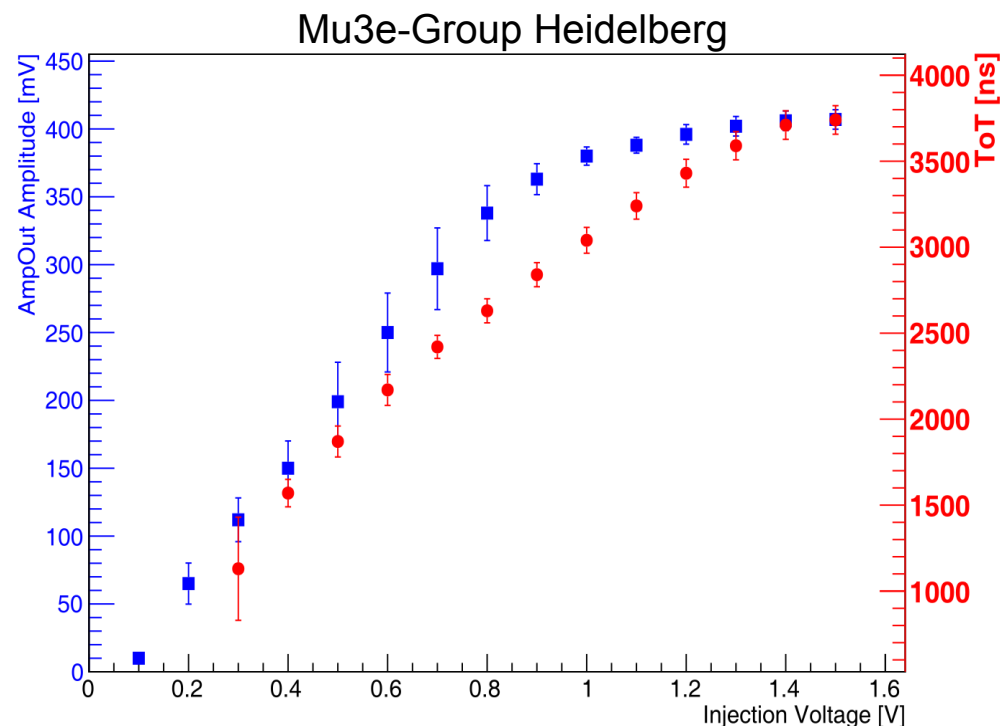
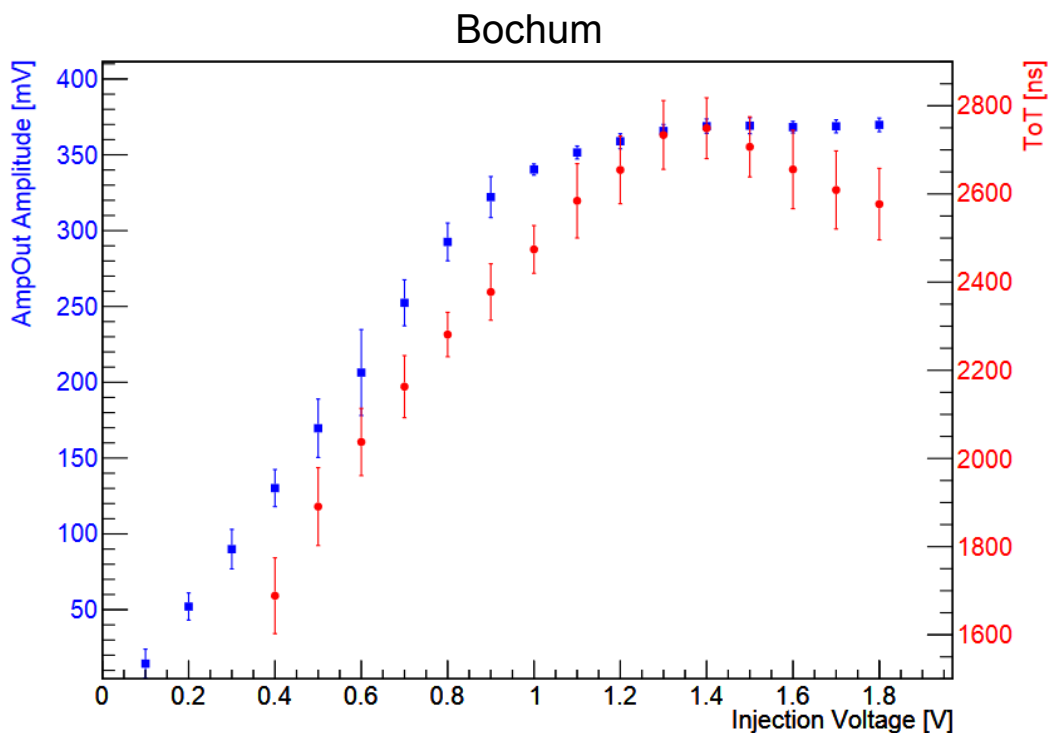
3



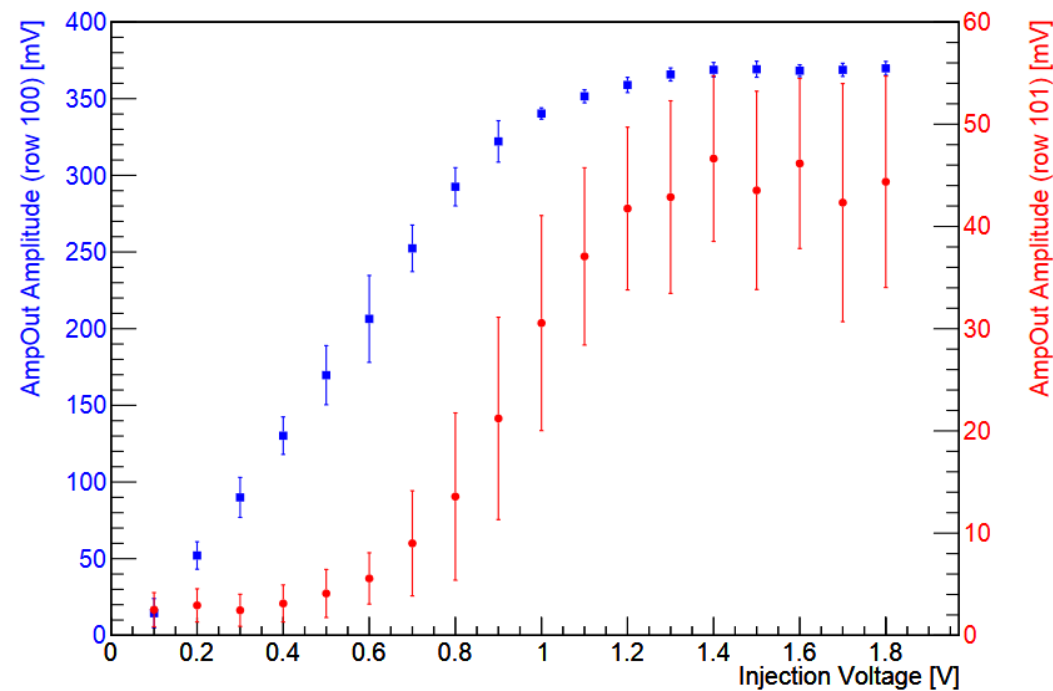
- ToT (measured with oscilloscope)
- Latency between injection pulse and chip response
- Plotted for different comparator thresholds



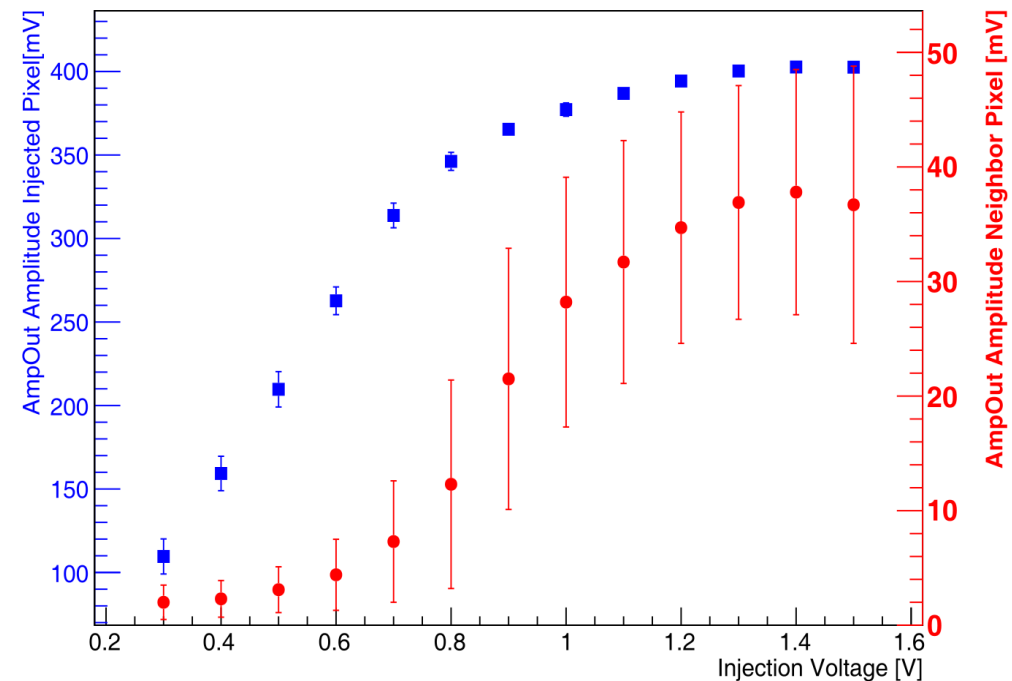
- Amplifier output saturates at ~ 400 mV
- Slight Saturation of ToT, followed by decrease at high injection voltages
- Might be an injection issue



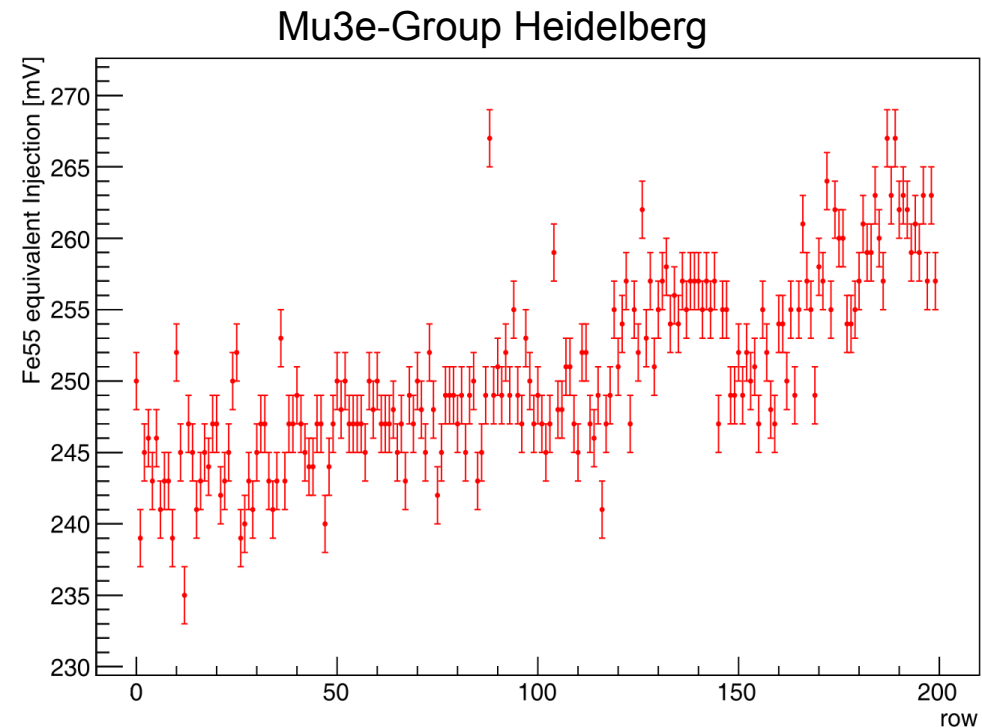
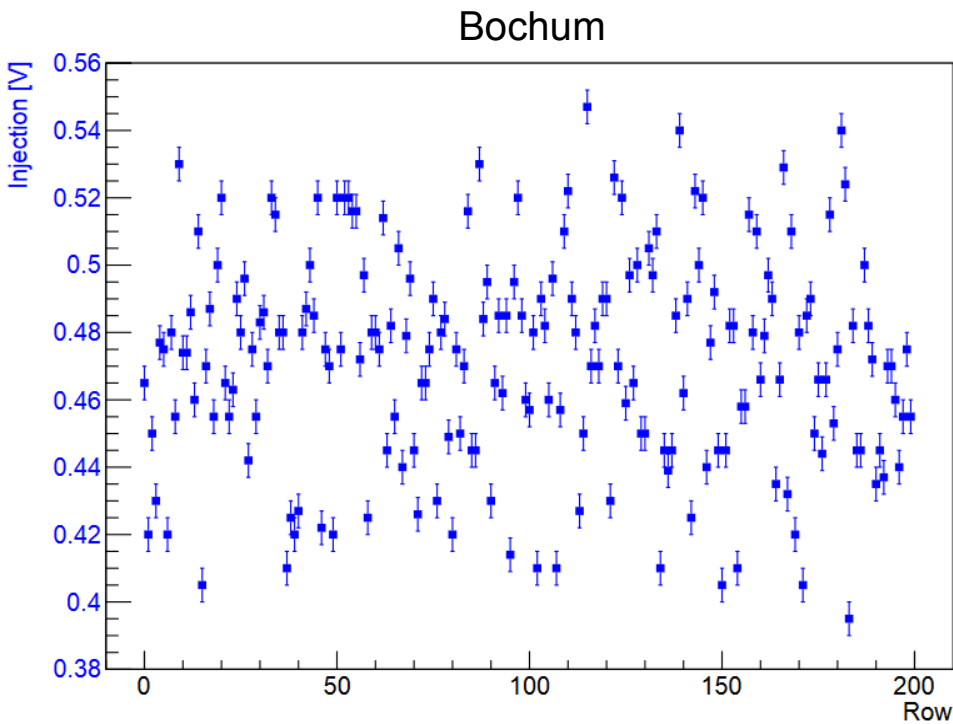
Bochum



Mu3e-Group Heidelberg

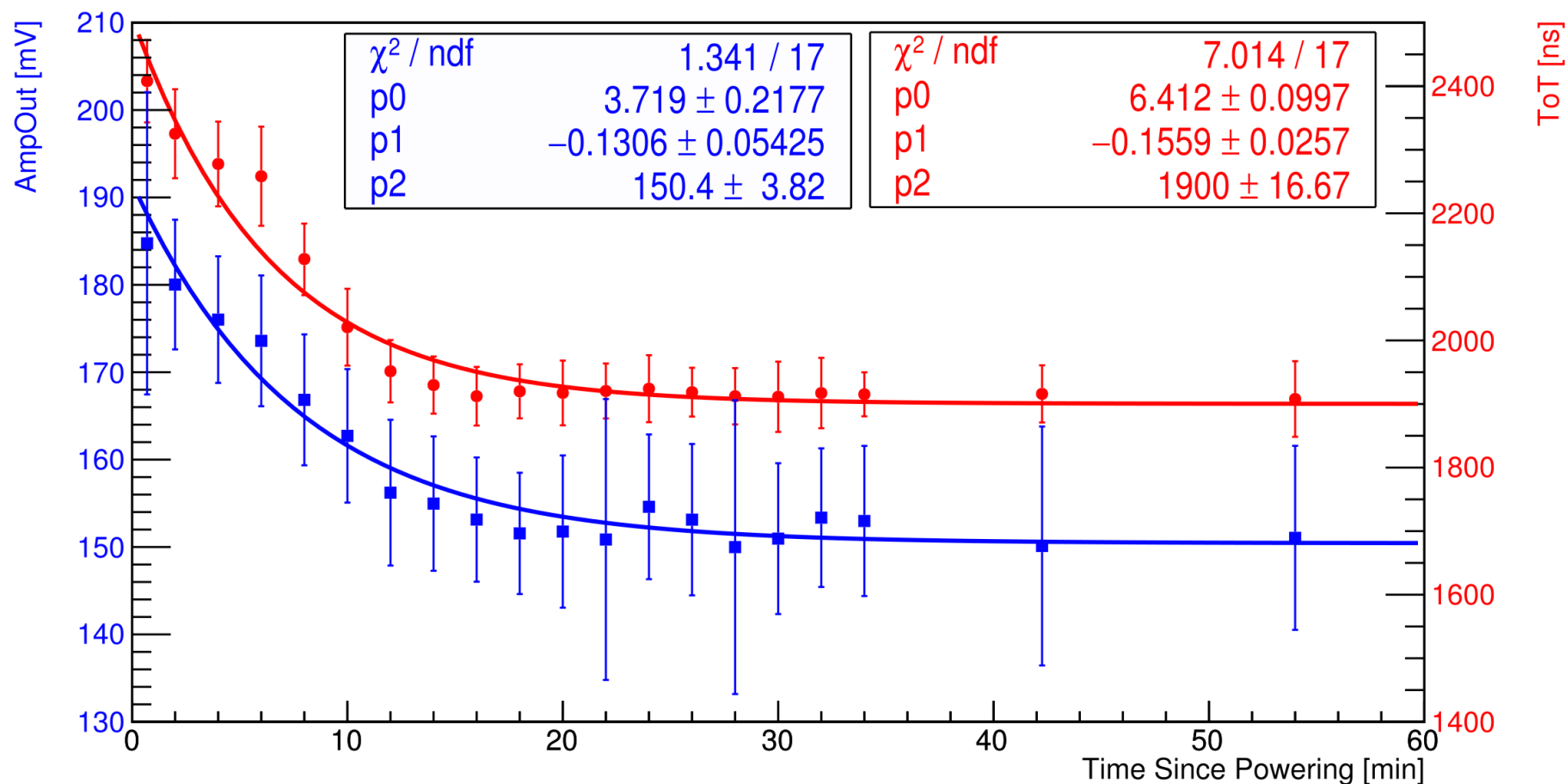


- AmpOut signal of injected pixel compared to signal measured at neighboring AmpOut
- Crosstalk $\lesssim 10\%$
- Upper limit of Crosstalk due to ampout saturation



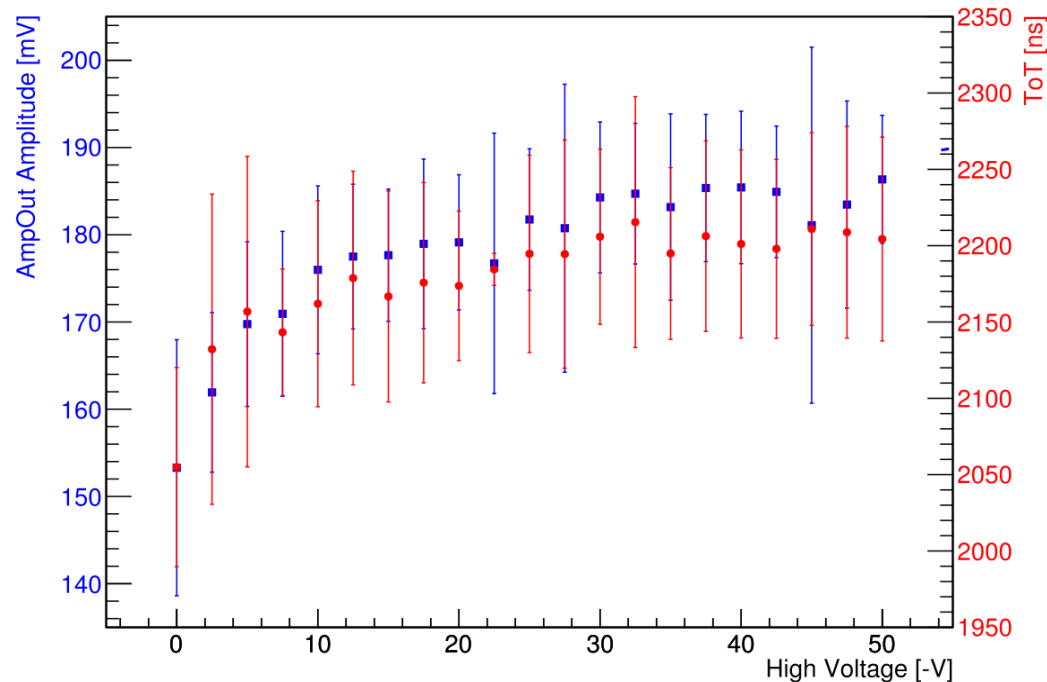
- Row dependent form could not be reproduced in Bochum
- Bochum: Injection adjusted to create AmpOut response of ~ 150 mV
- Heidelberg: Injection adjusted to create AmpOut response equivalent to that of a ^{55}Fe X-ray (5.9 keV)
→ Takes variations of individual pixels into account

- AmpOut amplitudes and ToTs show a decrease over time when powered after a longer downtime
- First believed to be a temperature effect (warm-up)
- Actually due to charging of feedback capacities

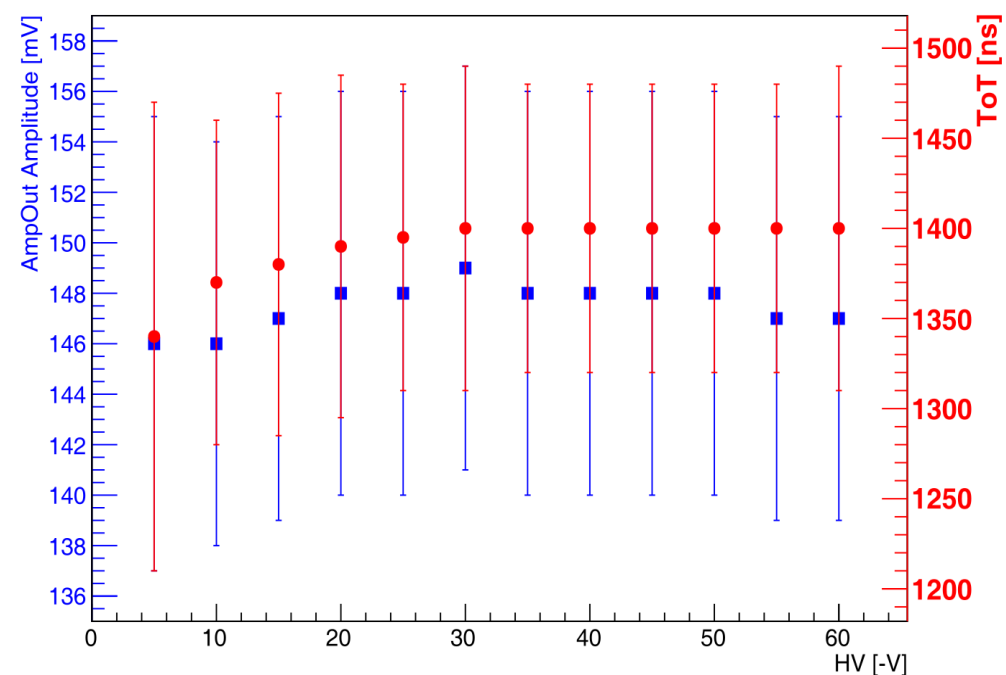


- Heidelberg: AmpOut amplitude and Hitbus ToTs show almost no dependence on HV
 - Bochum: clear rise of both signals with HV
- Still under investigation by Heidelberg group
might be due to different substrate resistivities (80 – 1k Ωcm)

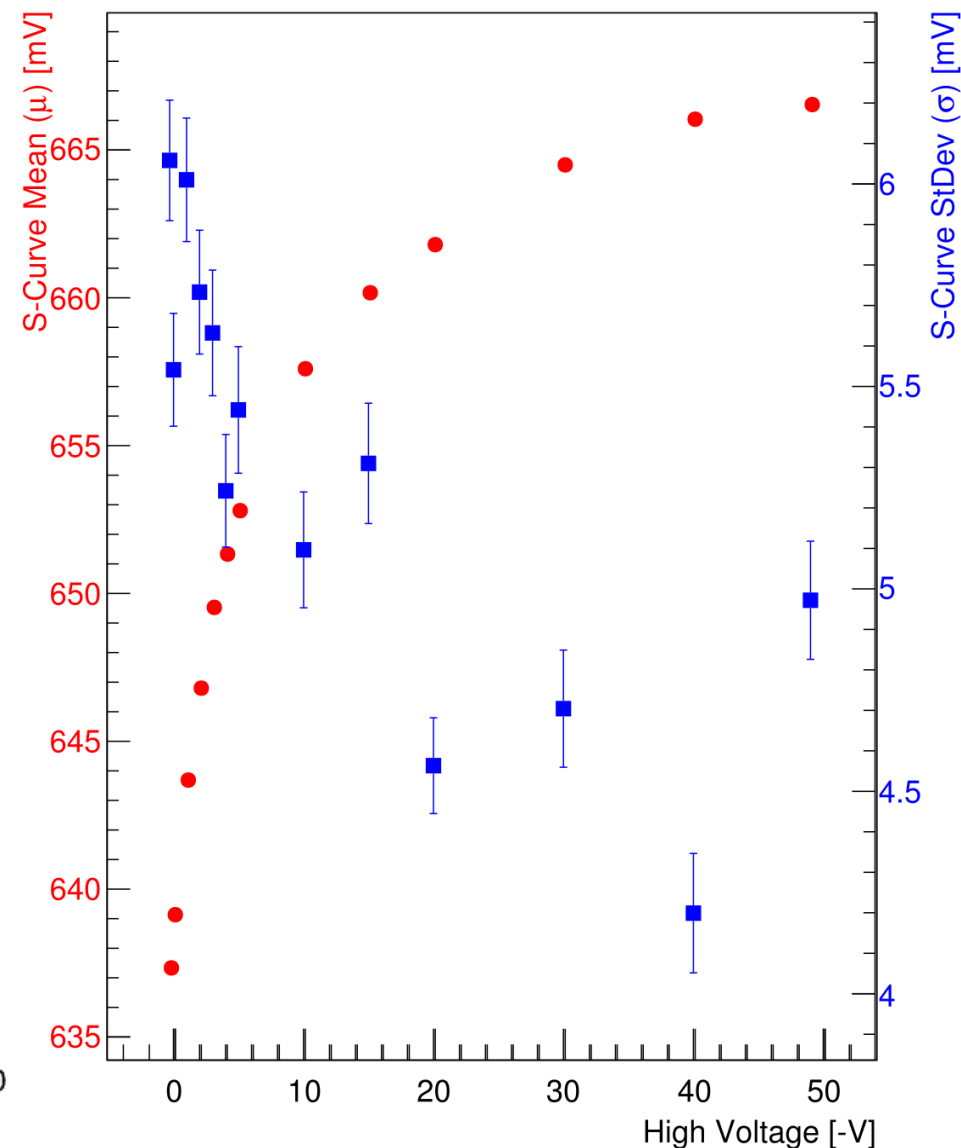
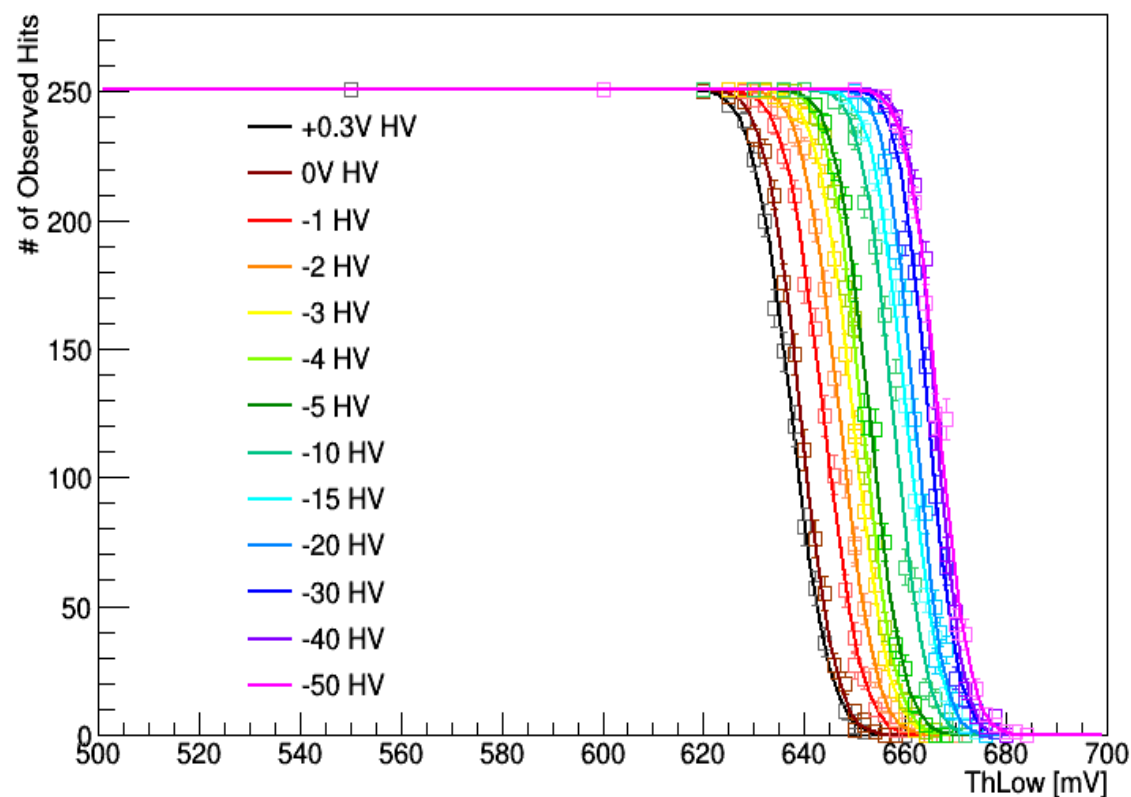
Bochum



Mu3e-Group Heidelberg

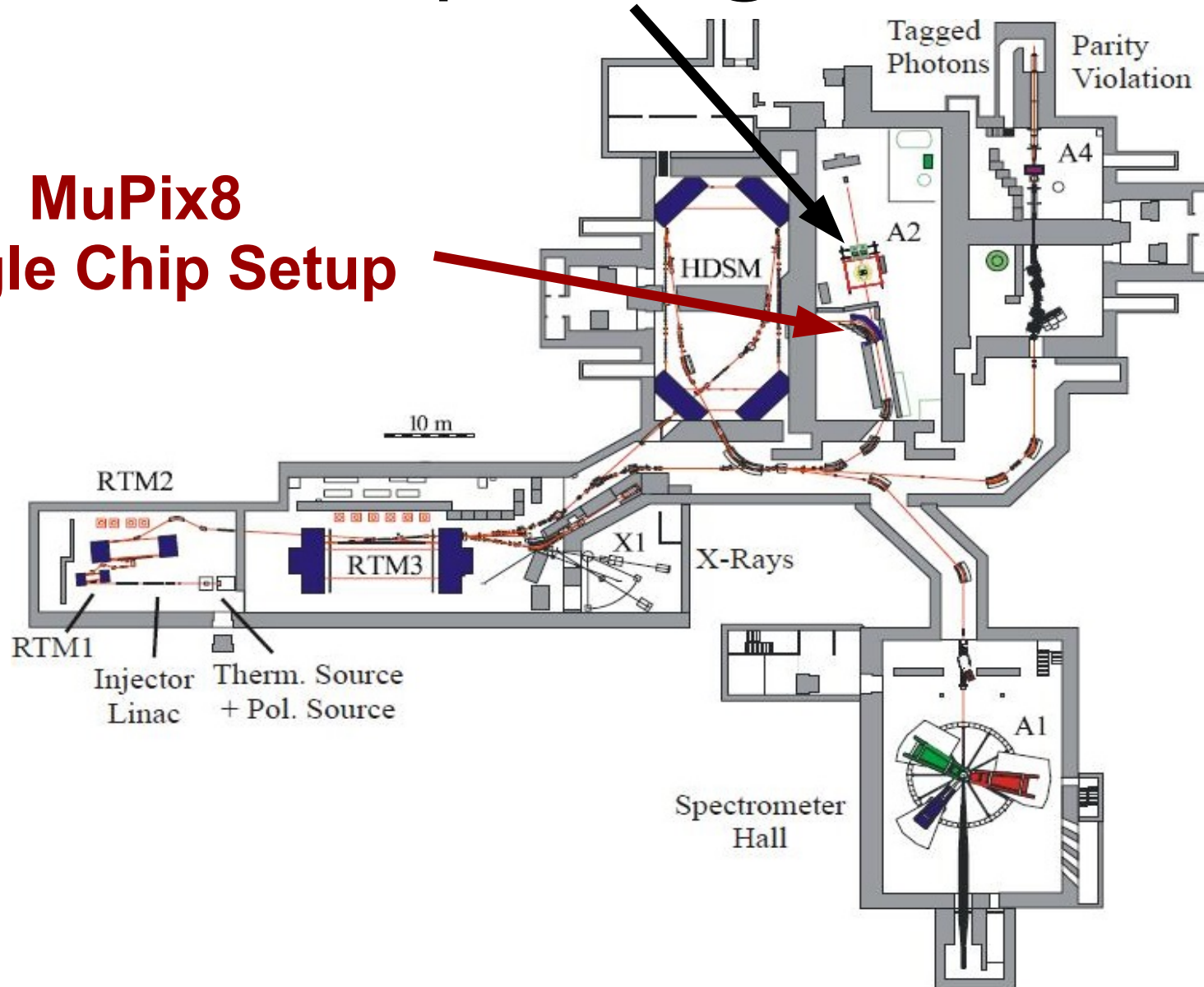


- Analog S-Curve measurements (oscilloscope counting events)
- Fitted with Gaussian error function
- $\text{SNR} = \frac{\mu - b}{\sigma}$, $b = 500 \text{ mV}$
- SNRs of $\sim 25 - 40$

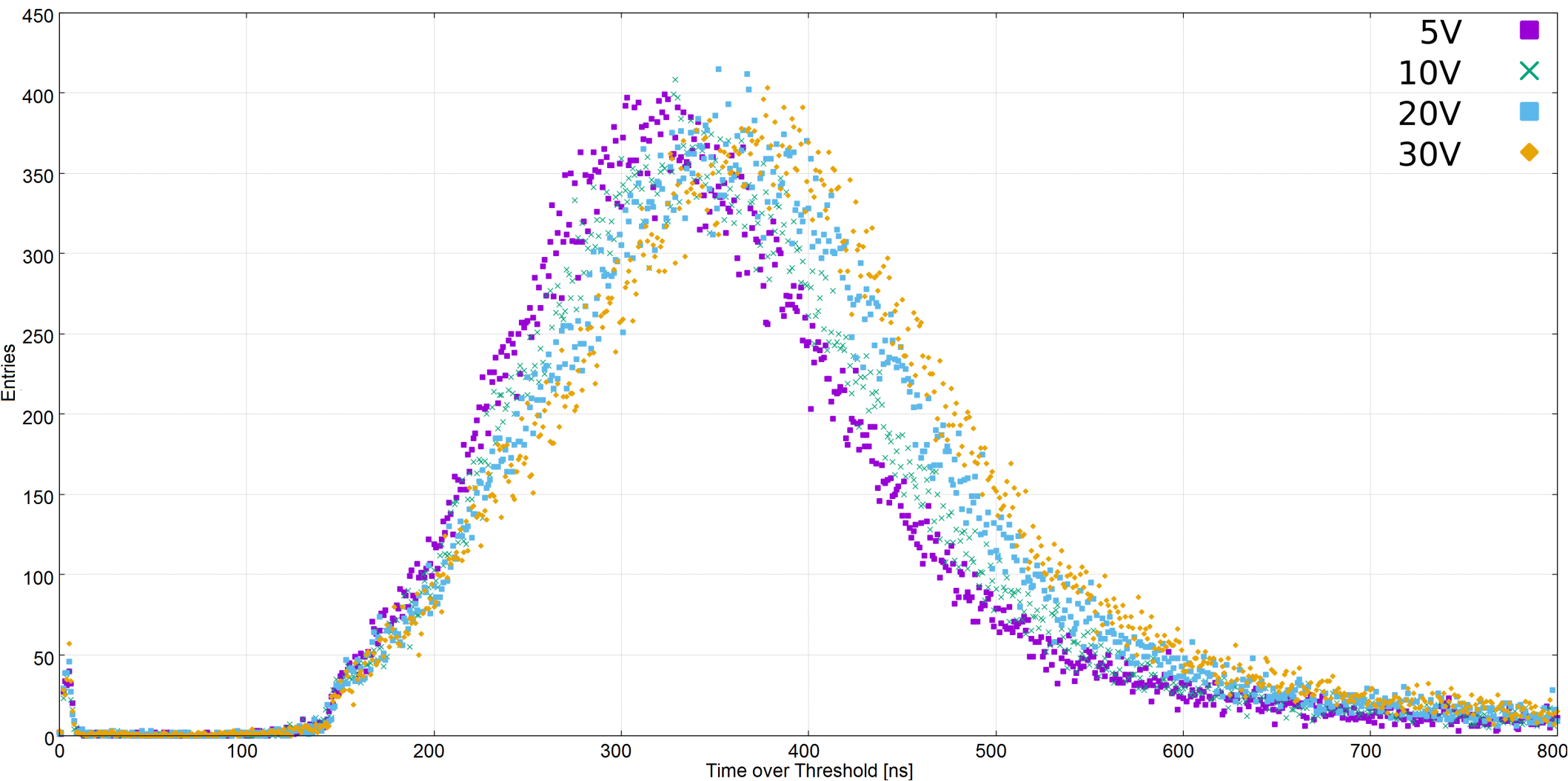


A2 Experiment @ MAMI

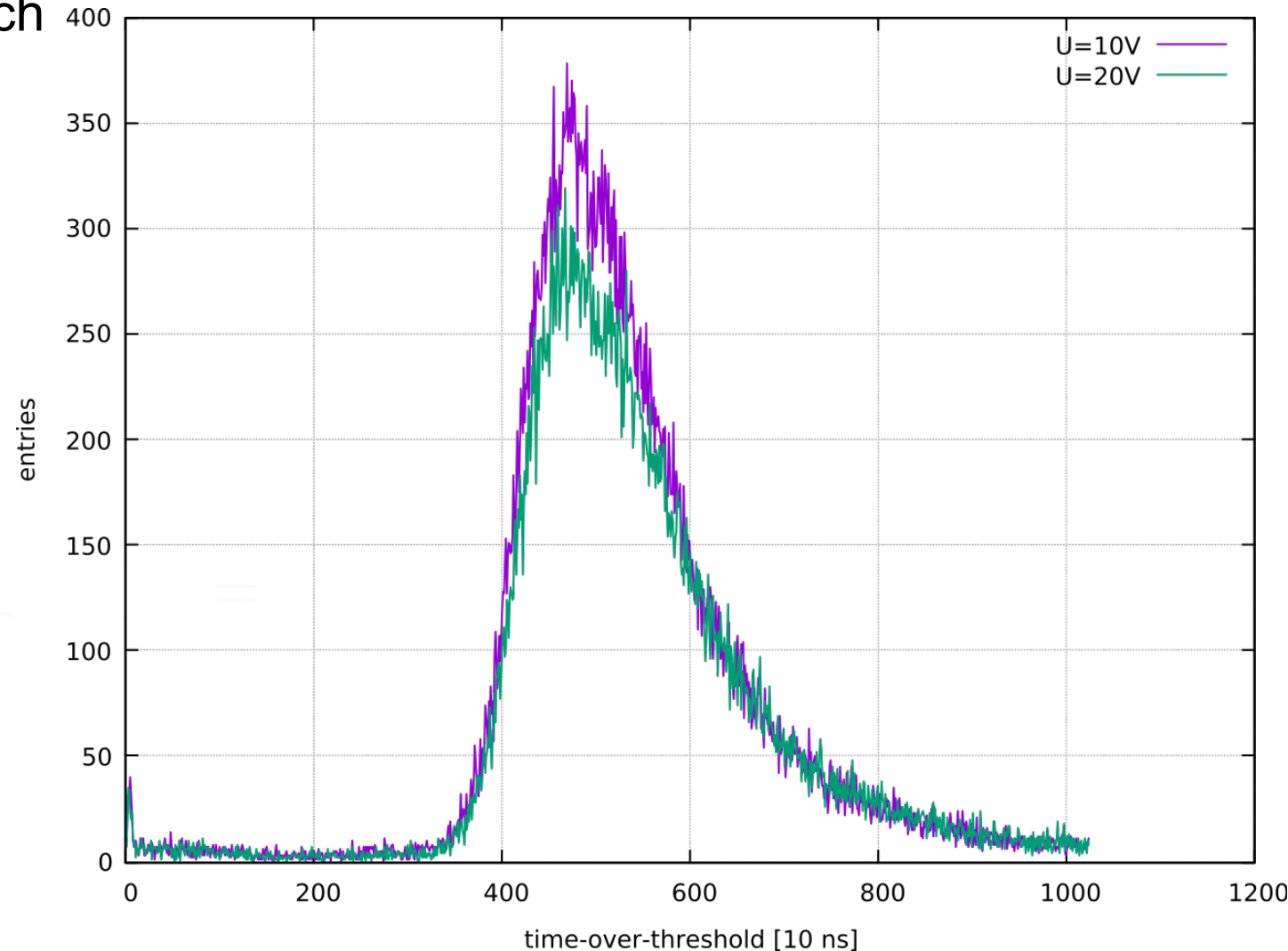
**MuPix8
Single Chip Setup**



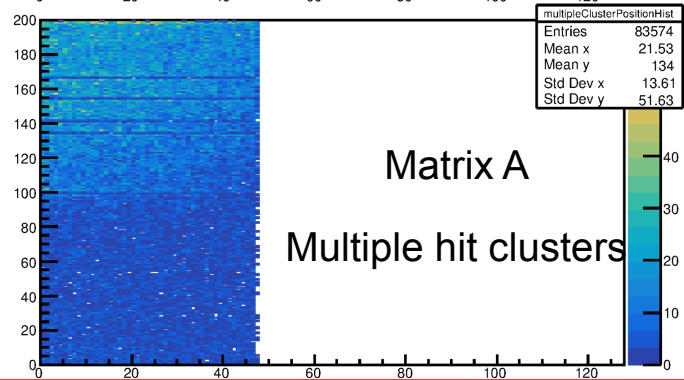
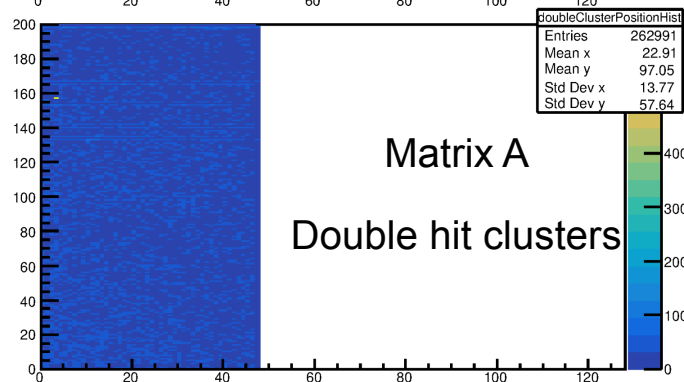
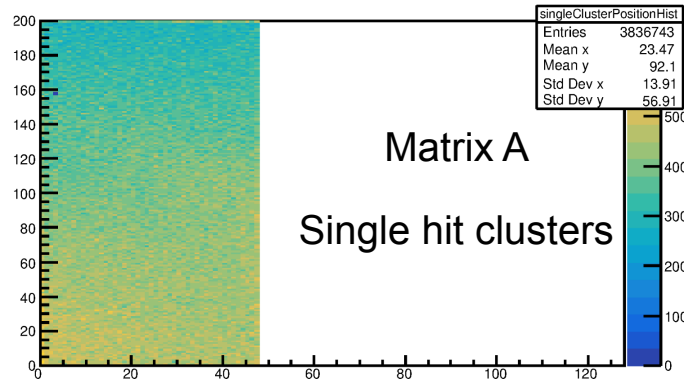
- ToTs for pixels in Matrix A and Matrix B at 570 mV threshold
- Clear HV dependence of ToT distribution for Matrix A



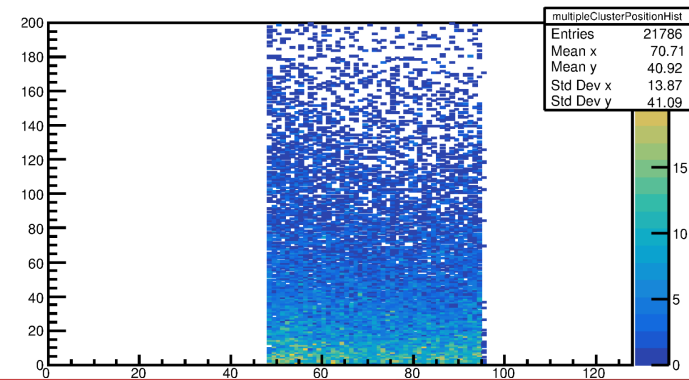
- ToTs for pixels in Matrix A and Matrix B at 570 mV threshold
- Clear HV dependence of ToT distribution for Matrix A
- Matrix B – not so much



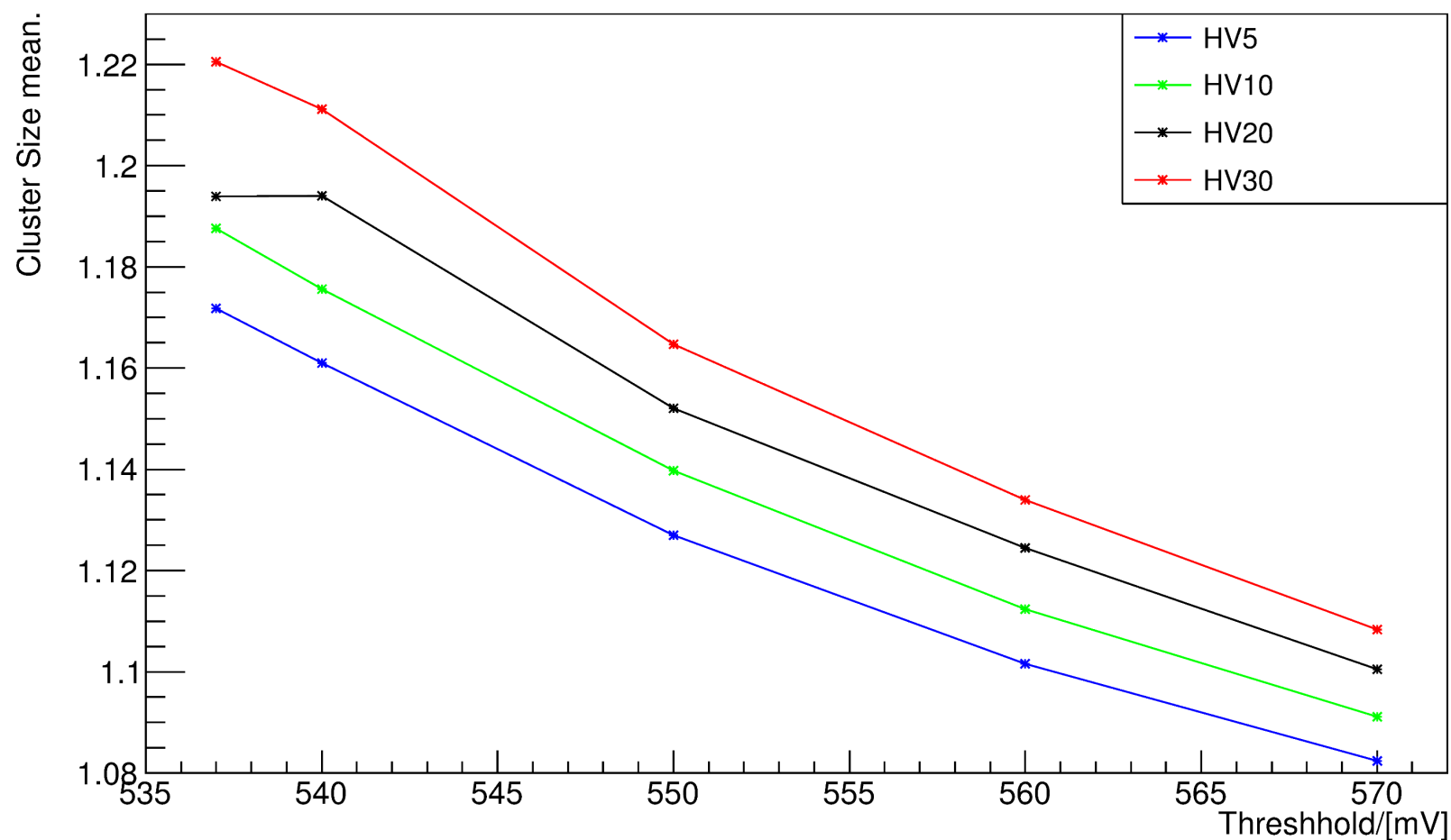
- Different cluster sizes show different distributions
- Matrix B behaves differently ...again



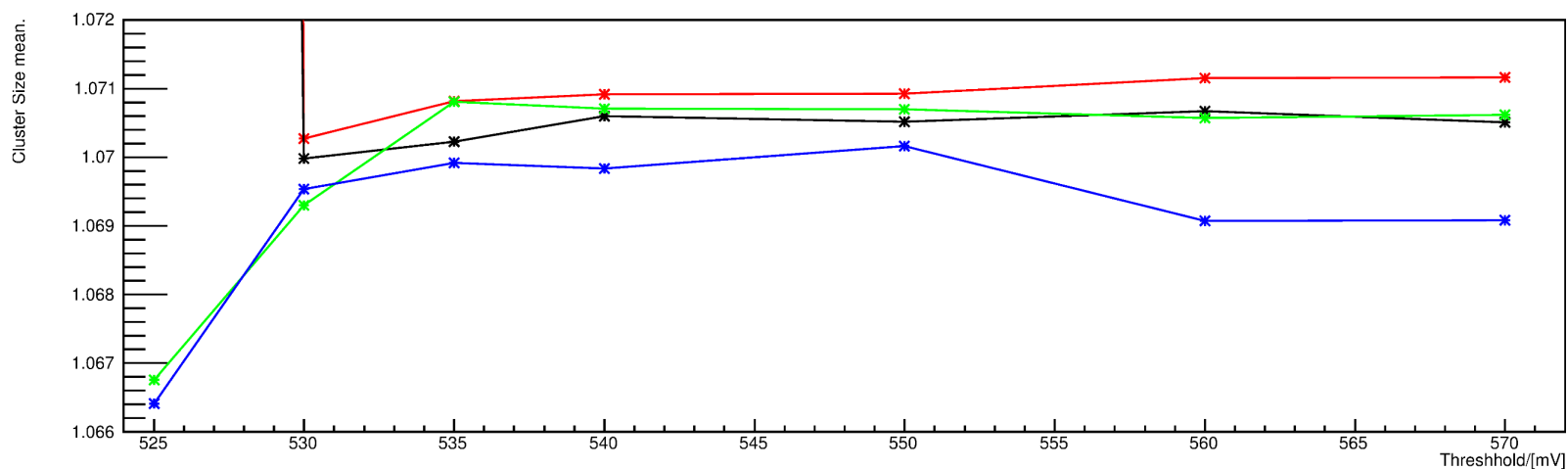
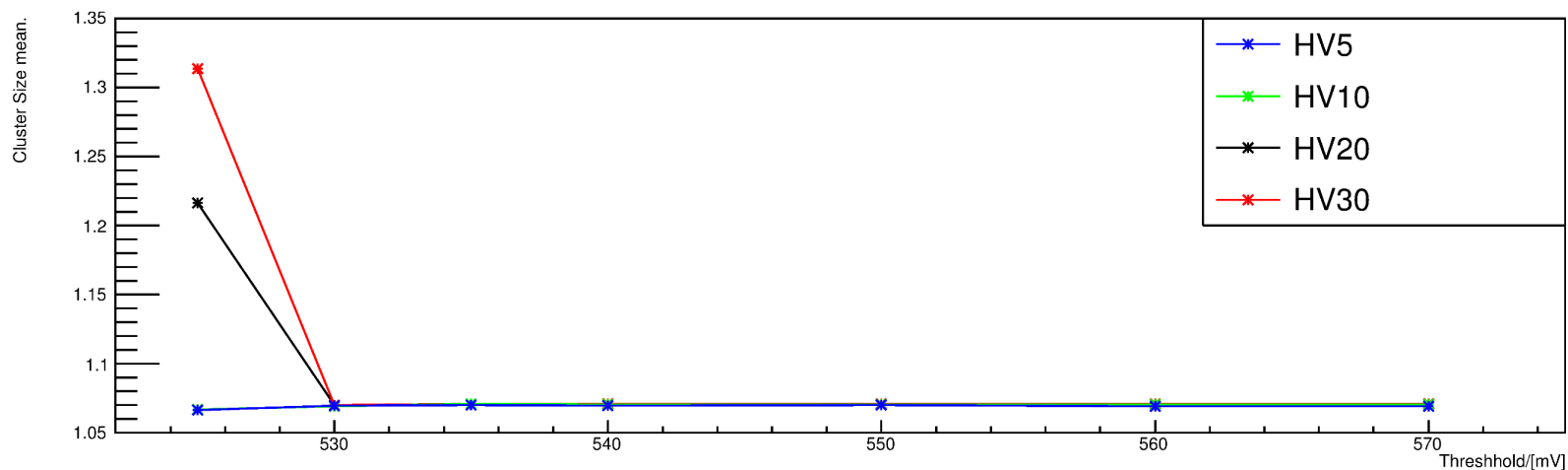
Matrix B
Multiple hit clusters



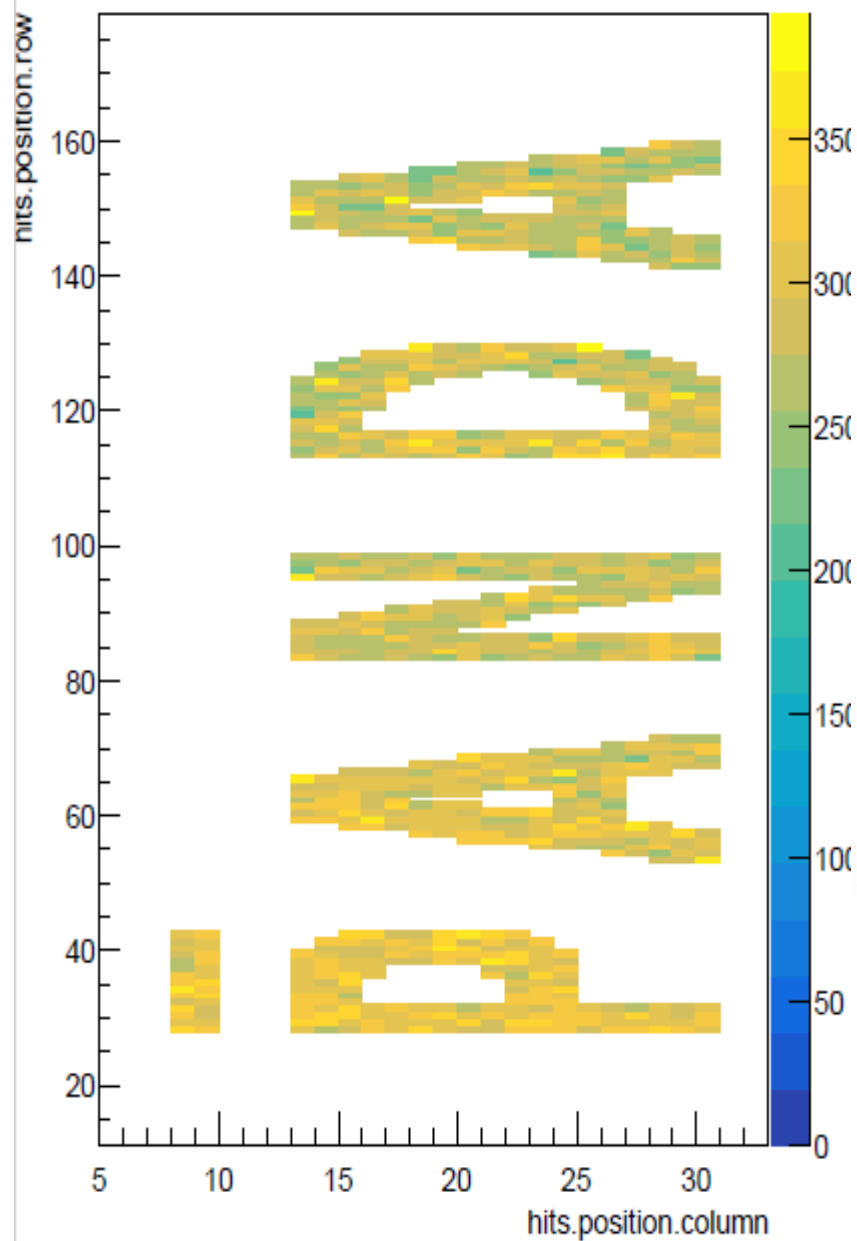
- Average cluster size for Matrix A shows clear HV and threshold dependence



- Average cluster size for Matrix A shows clear HV and threshold dependence
- Clusters in Matrix B are (almost) constant for all HVs and thresholds



- Analog properties (AmpOut, Hitbus) tested in lab setup
- Comparison with Heidelberg results:
 - Validation of saturation behavior and crosstalk strength
 - Row dependence measurements inconclusive (**^{55}Fe source**)
 - HV dependence still under investigation (**substrate resistivities**)
- First testbeam measurements with Bochum setup
- ToT spectra and cluster analyses:
 - Matrix A (old design, source follower) behaves as expected
 - Matrix B/C (current driver) still has some issues



**Thank you
for your
attention !!**

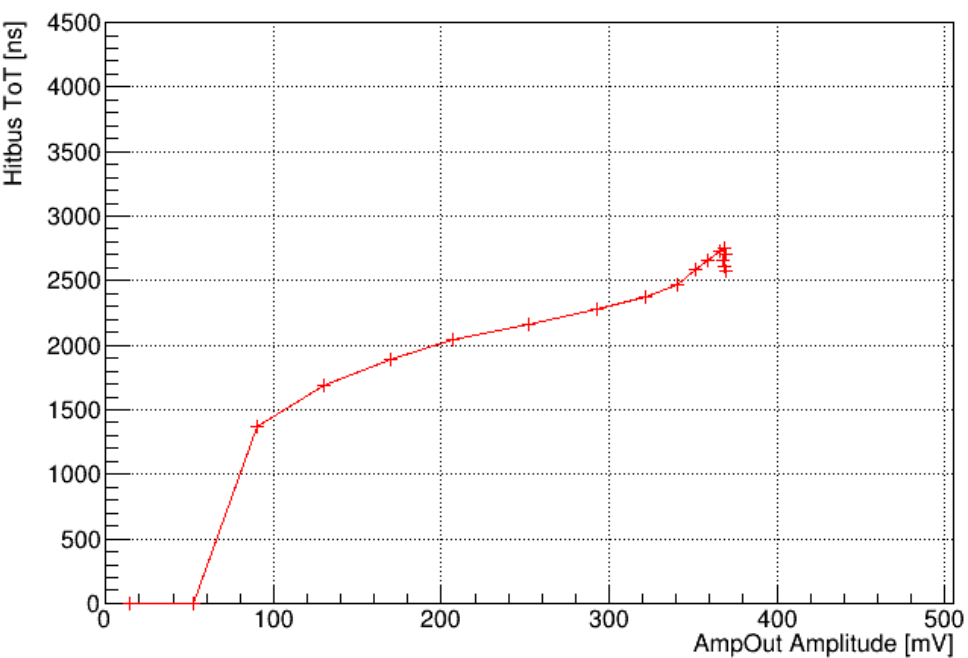
– Backup –

AmpOut vs Hitbus

Bochum

Signal source: Injections

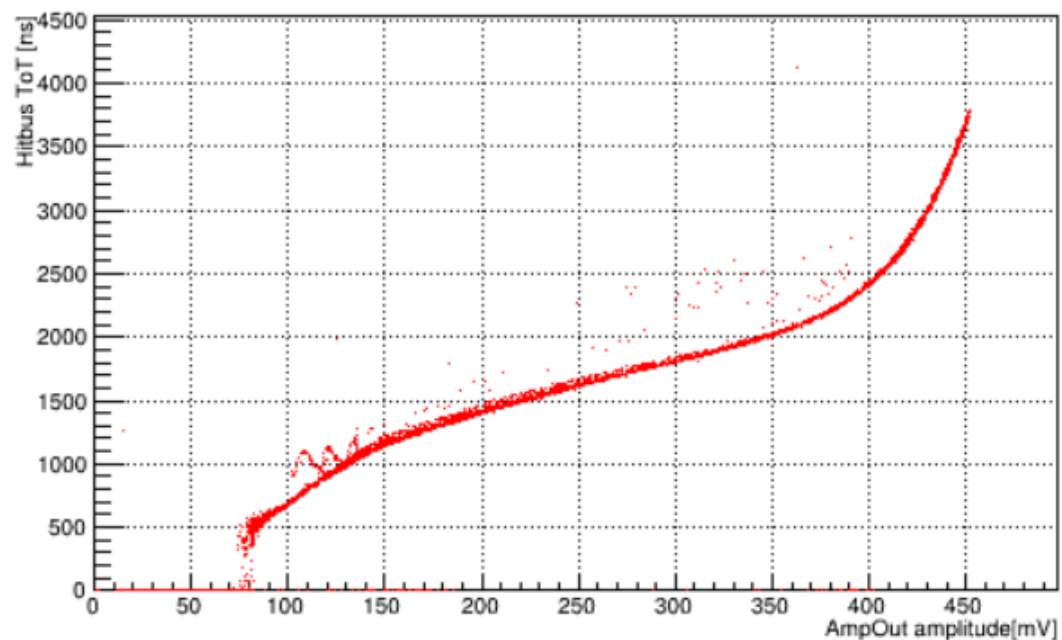
AmpOut vs. Hitbus



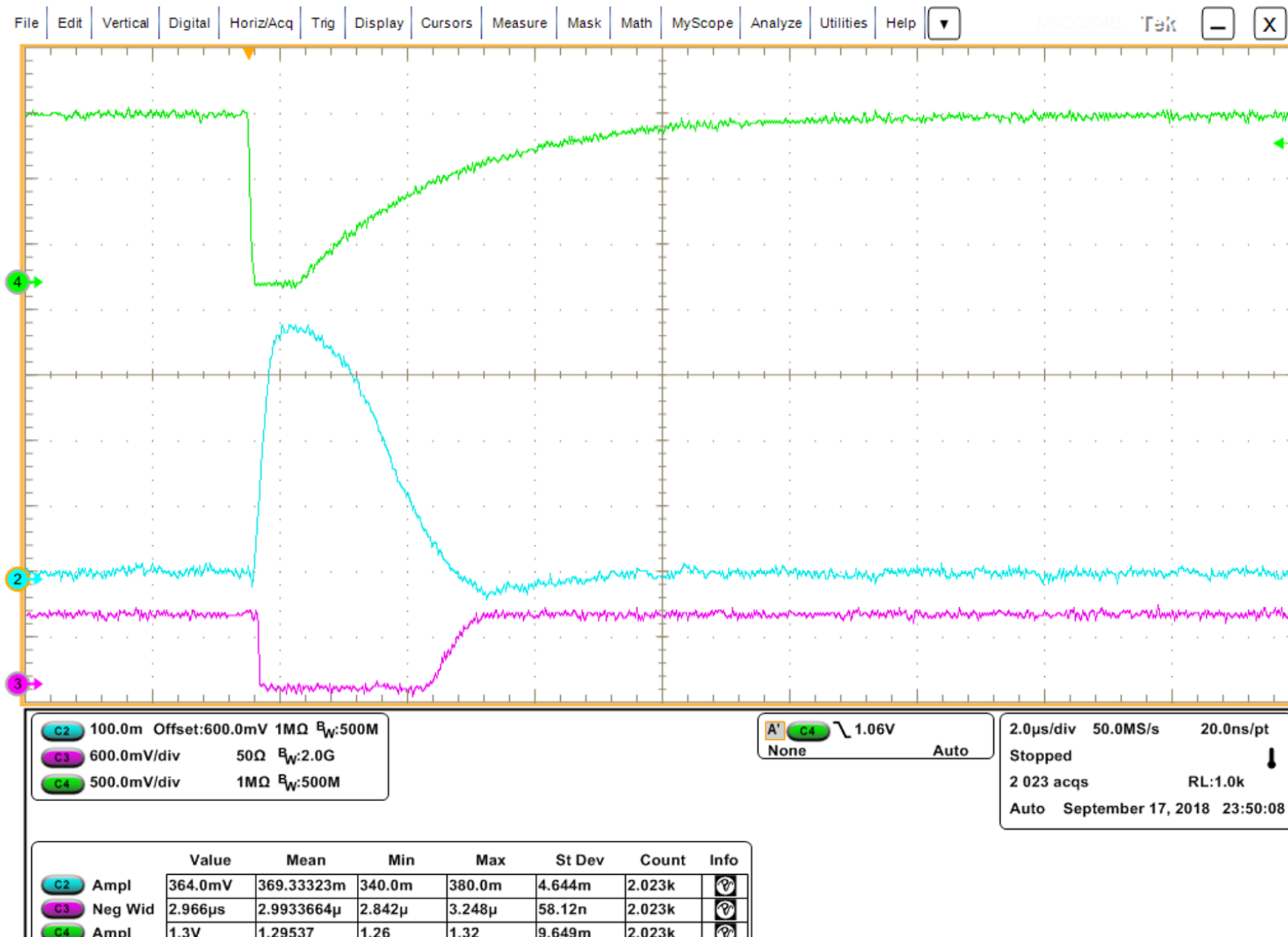
Mu3e-Group Heidelberg

Signal source: IR-Laser

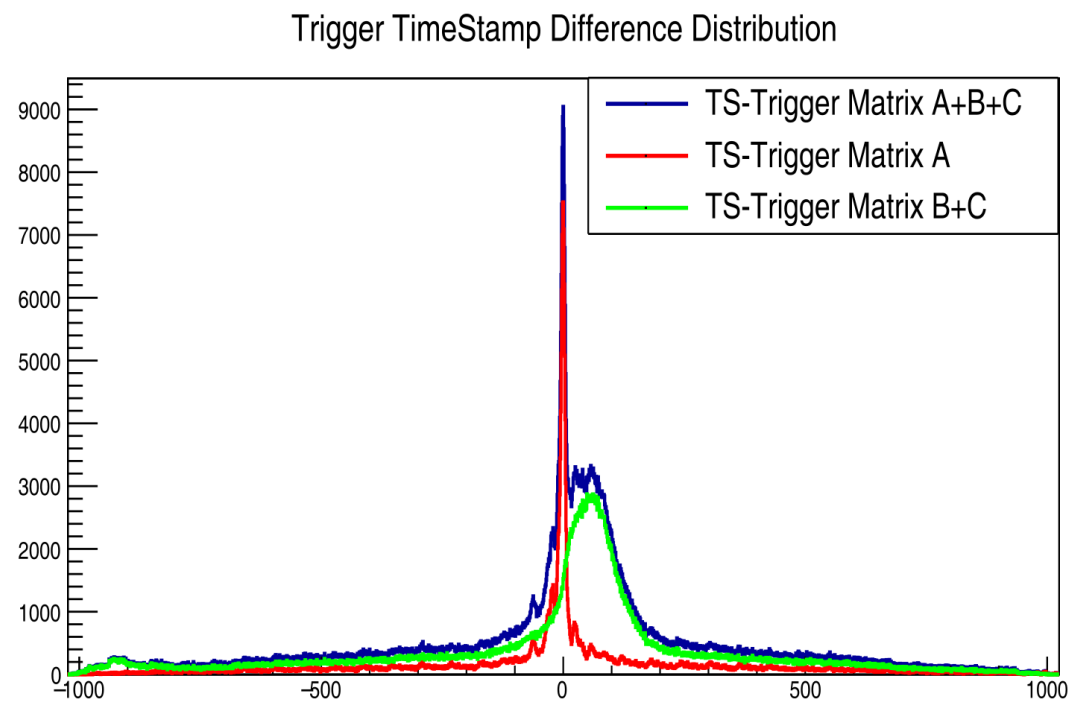
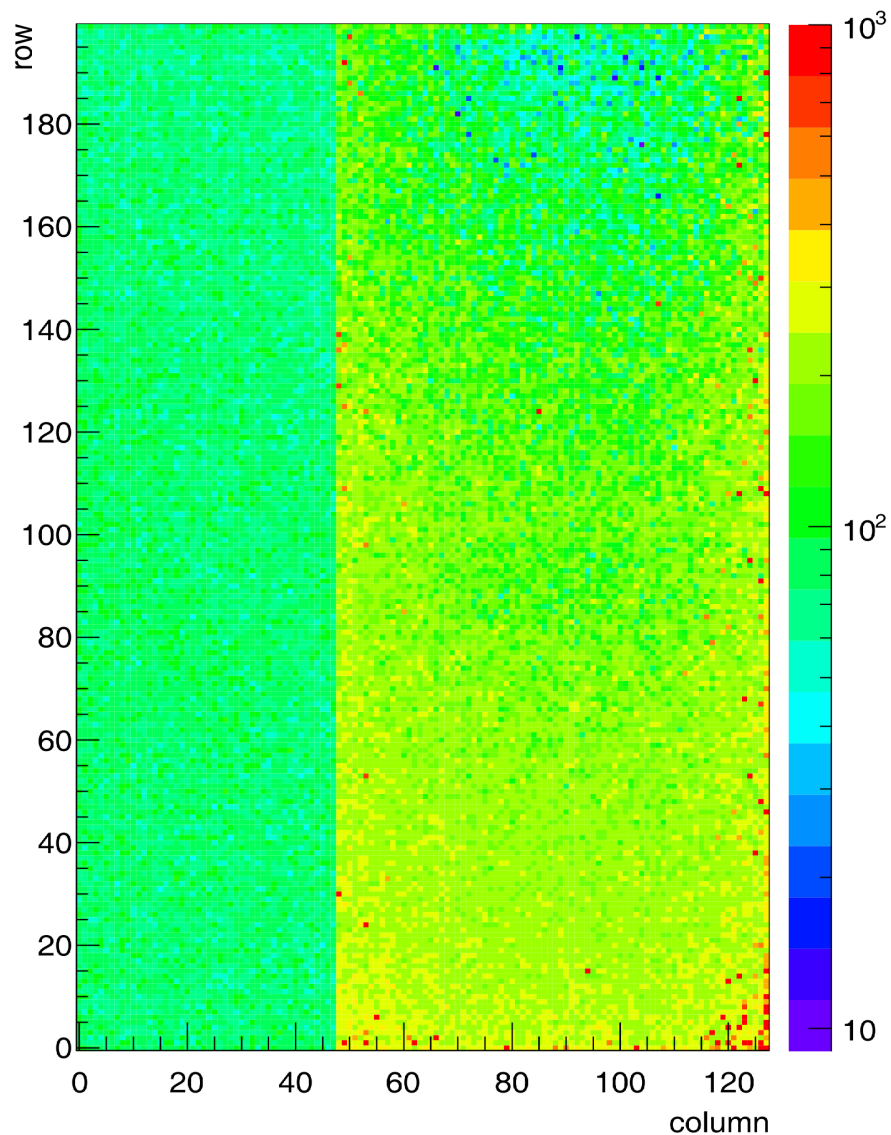
AmpOut Amp. vs. Hitbus ToT



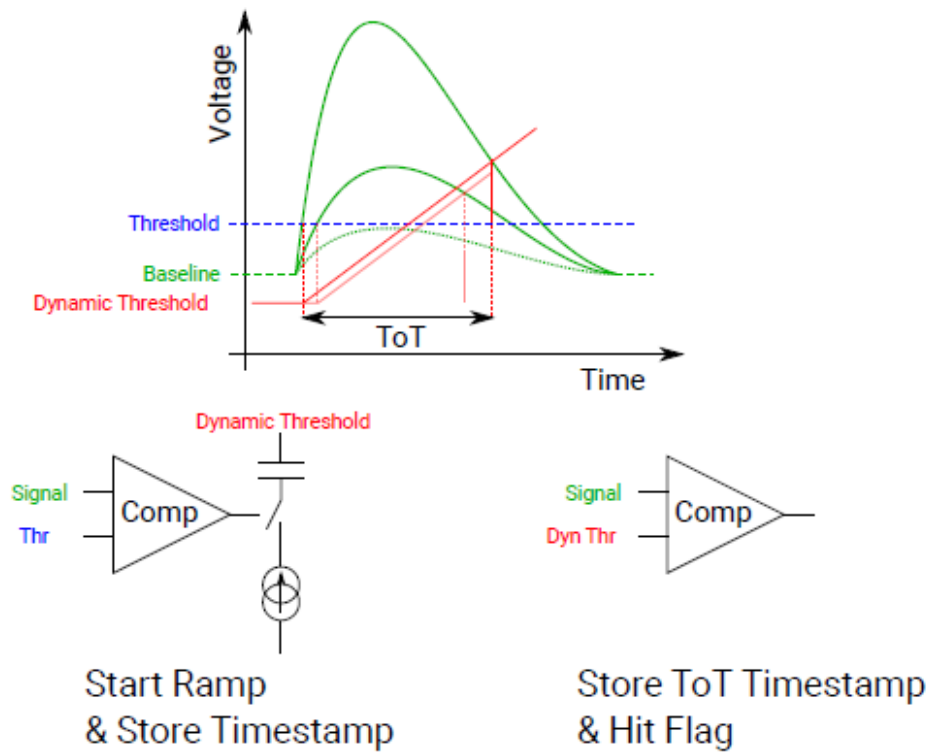
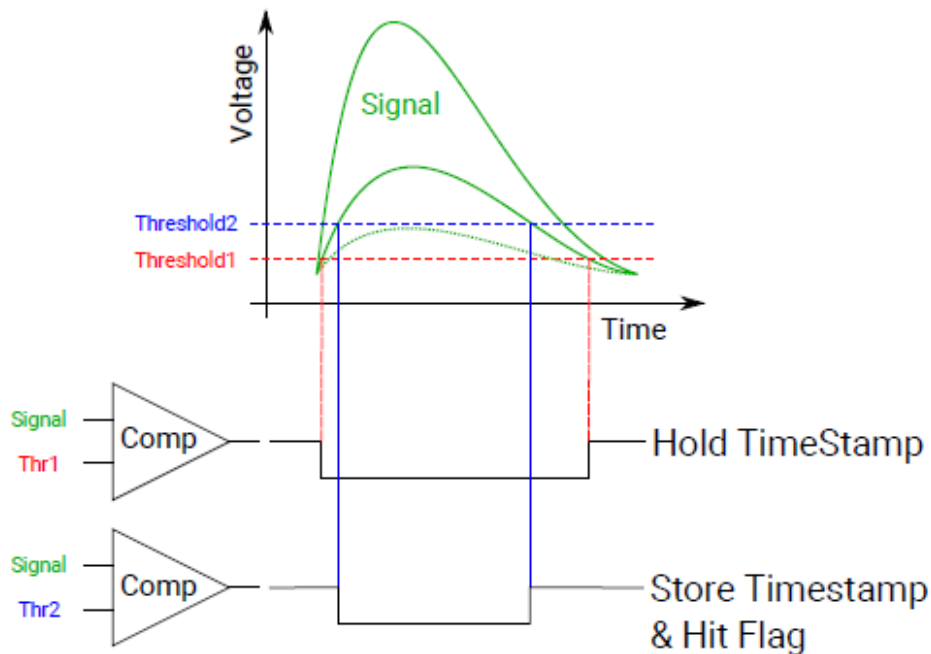
AmpOut on Oscilloscope



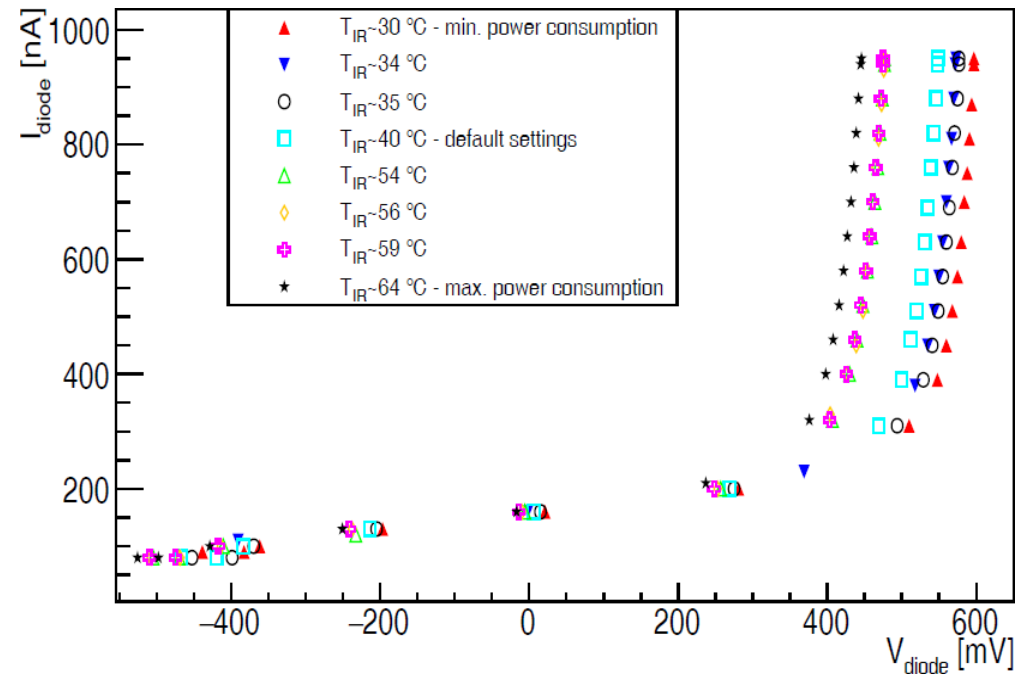
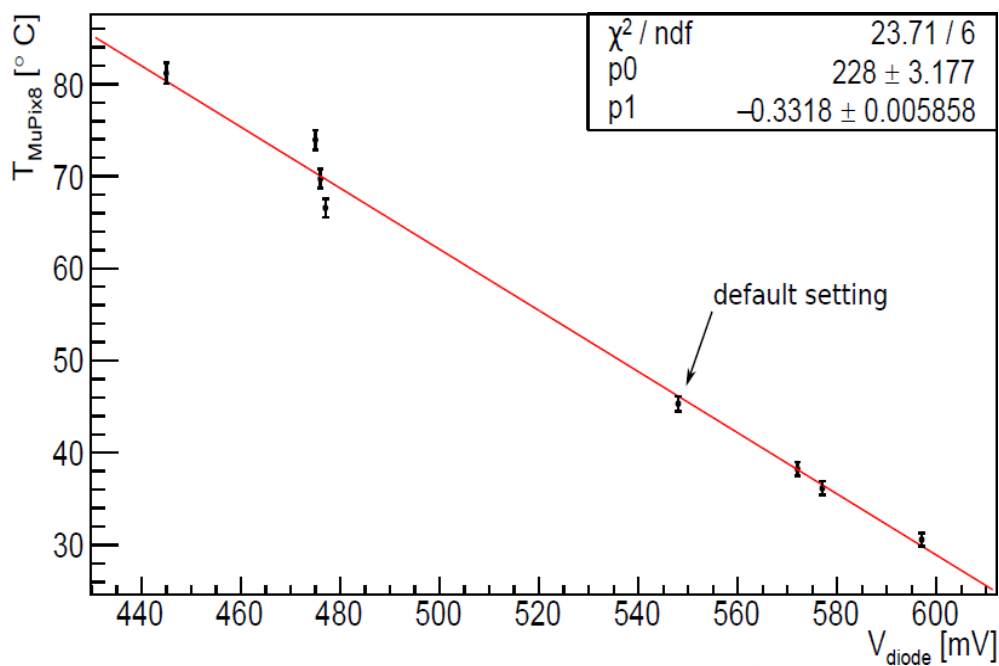
Submatrices



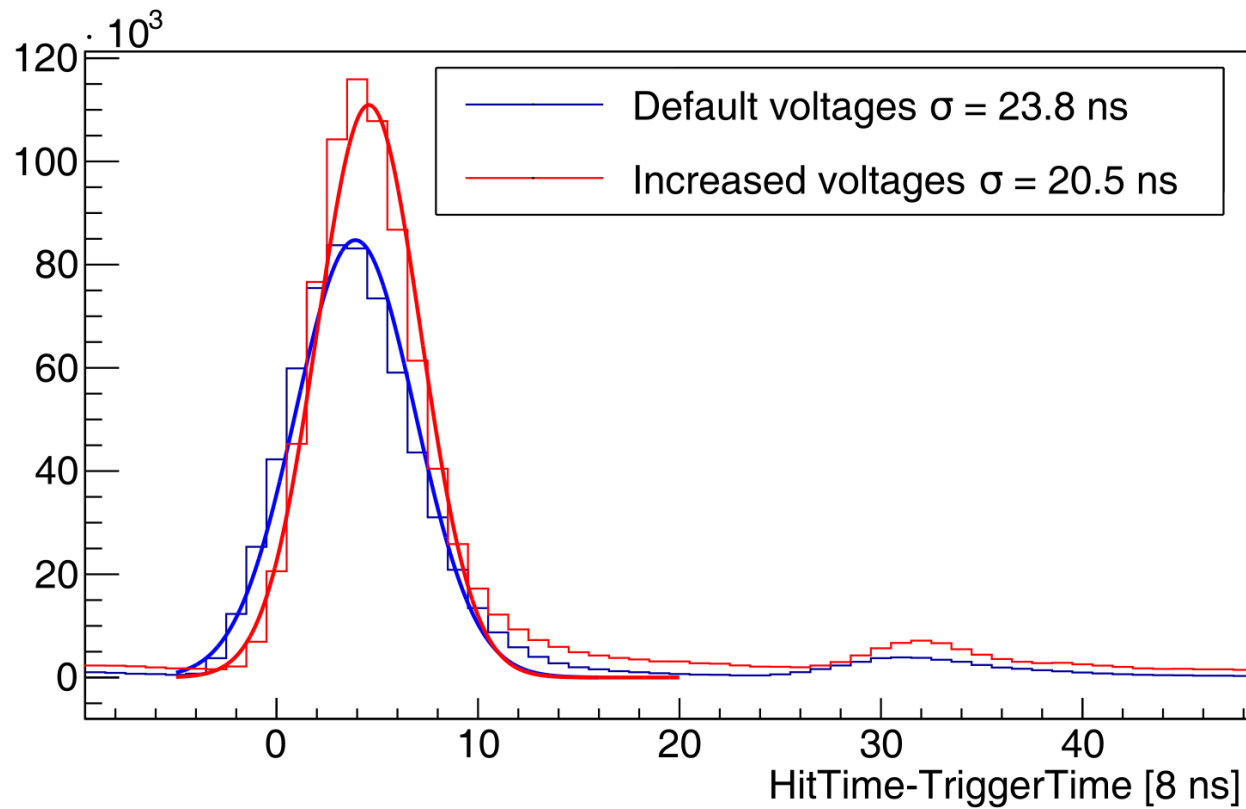
Timewalk Compensation



Temperature Diode



Timing with Increased Supply Voltage



Row (In-)Dependence of ^{55}Fe -Signal

